Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/602,194	ONO, YOSHI	
Examiner	Art Unit	
Khiem D. Nguyen	2823	

	SEARCHED			
Class	Subclass	Date	Examiner	
			<u> </u>	
		:		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
_				
-	.1			
,				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE	3/9/2005	K.N.